



# STSJ100NH3LL

## N-CHANNEL 30 V - 0.0032 Ω - 25 A PowerSO-8™ STripFET™ III MOSFET FOR DC-DC CONVERSION

**Table 1: General Features**

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STSJ100NH3LL	30V	< 0.0035Ω	25A

- TYPICAL R<sub>DS(on)</sub> = 0.0032Ω @ 10V
- OPTIMAL R<sub>DS(on)</sub> x Q<sub>g</sub> TRADE-OFF @ 4.5V
- SWITCHING LOSSES REDUCED
- LOW THRESHOLD DEVICE
- IMPROVED JUNCTION-CASE THERMAL RESISTANCE

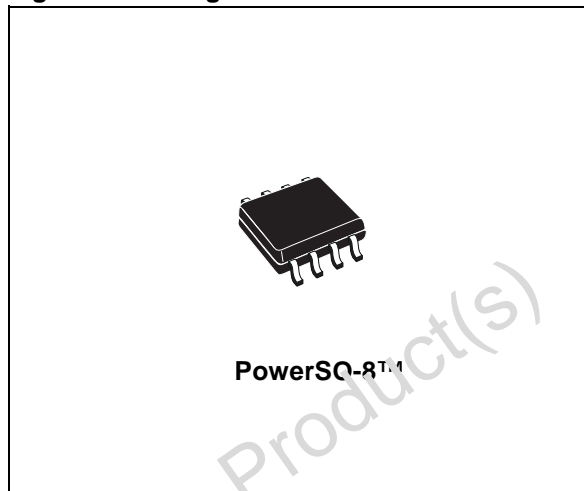
### DESCRIPTION

The **STSJ100NH3LL** utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. This process coupled to unique metallization techniques realizes the most advanced low voltage MOSFET in SO-8 ever produced. The exposed slug reduces the R<sub>thj-c</sub> improving the current capability.

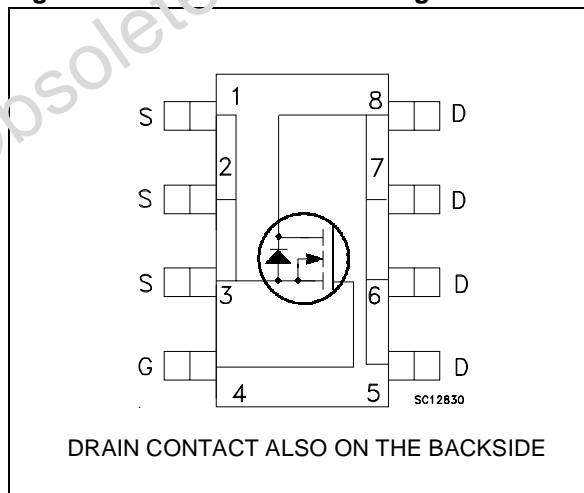
### APPLICATIONS

- SPECIFICALLY DESIGNED AND OPTIMISED FOR HIGH EFFICIENCY CPU CORE DC/DC CONVERTERS FOR MOBILE PCs

**Figure 1: Package**



**Figure 2: Internal Schematic Diagram**



**Table 2: Order Codes**

SALES TYPE	MARKING	PACKAGE	PACKAGING
STSJ100NH3LL	100H3LL-	PowerSO-8	TAPE & REEL

**Table 3: Absolute Maximum ratings**

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	30	V
V <sub>GS</sub>	Gate- source Voltage	± 16	V
I <sub>D</sub> (2)	Drain Current (continuous) at T <sub>C</sub> = 25°C	100	A
I <sub>D</sub> (1)	Drain Current (continuous) at T <sub>C</sub> = 25°C	25	A
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 100°C	15.6	A
I <sub>DM</sub> (3)	Drain Current (pulsed)	100	A
P <sub>tot</sub> (2)	Total Dissipation at T <sub>C</sub> = 25°C	70	W
P <sub>tot</sub> (1)	Total Dissipation at T <sub>C</sub> = 25°C	3	W

**Table 4: Thermal Data**

R <sub>thj-c</sub>	Thermal Resistance Junction-case	Max	1.8	°C/W
R <sub>thj-pcb</sub> (4)	Thermal Resistance Junction-ambient	Max	42	°C/W
T <sub>j</sub>	Maximum Operating Junction Temperature		150	°C
T <sub>stg</sub>	Storage Temperature		-55 to 150	°C

**Table 5: Avalanche Characteristics**

Symbol	Parameter	Max Value	Unit
I <sub>AV</sub>	Not-Repetitive Avalanche Current (pulse width limited by T <sub>j</sub> max)	12.5	A
E <sub>AS</sub>	Single Pulse Avalanche Energy (starting T <sub>j</sub> = 25 °C, I <sub>D</sub> = I <sub>AV</sub> , V <sub>DD</sub> = 24 V)	1.3	J

**ELECTRICAL CHARACTERISTICS (T<sub>CASE</sub> =25°C UNLESS OTHERWISE SPECIFIED)**

**Table 6: On /Off**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	I <sub>D</sub> = 250µA, V <sub>GS</sub> = 0	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max Rating V <sub>DS</sub> =Max Rating , T <sub>C</sub> = 125°C			1 10	µA µA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 16V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250µA	1			V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 12.5A V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 12.5A		0.0032 0.004	0.0035 0.005	Ω Ω

## ELECTRICAL CHARACTERISTICS (CONTINUED)

Table 7: Dynamic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$g_{fs}$ (5)	Forward Transconductance	$V_{DS}=10V, I_D = 12.5A$		30		S
$C_{iss}$ $C_{oss}$ $C_{rss}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V, f = 1 \text{ MHz}, V_{GS} = 0$		4450 655 50		pF pF pF
$R_G$	Gate Input Resistance	$f=1\text{MHz}$ Gate DC Bias = 0 Test Signal Level = 20mV Open Drain	1	2	3	$\Omega$

Table 8: Switching On

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ $t_r$	Turn-on Delay Time Rise Time	$V_{DD} = 15V, I_D = 12.5A$ $R_G = 4.7\Omega, V_{GS} = 10V$ (see Figure 15)		18 50		ns ns
$Q_g$ $Q_{gs}$ $Q_{gd}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD}=15V, I_D=25A$ $V_{GS}=4.5V$ (see Figure 17)		30 12.5 10	40	nC nC nC

Table 9: Switching Off

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$ $t_f$	Turn-off Delay Time Fall Time	$V_{DD} = 15V, I_D = 12.5A$ $R_G = 4.7\Omega, V_{GS} = 10V$ (see Figure 15)		75 8		ns ns

Table 10: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$I_{SD}$ $I_{SDM}$	Source-drain Current Source-drain Current (pulsed)				25 100	A A
$V_{SD(5)}$	Forward On Voltage	$I_{SD} = 25A, V_{GS} = 0$			1.3	V
$t_{rr}$ $Q_{rr}$ $I_{RRM}$	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 25A, di/dt = 100A/\mu s$ $V_{DD} = 25V, T_j = 150^\circ C$ (see Figure 16)		32 34 2.1		ns nC A

## Notes

1. This value is noted according to  $R_{thj-pcb}$
2. This value is noted according to  $R_{thj-c}$
3. Pulse width limited by safe operating area
4. When Mounted on 1 inch<sup>2</sup> FR-4 board, 2 oz Cu ( $t \leq 10$  sec.)
5. Pulsed: pulse duration=300 $\mu s$ , duty cycle 1.5%

Figure 3: Safe Operating Area

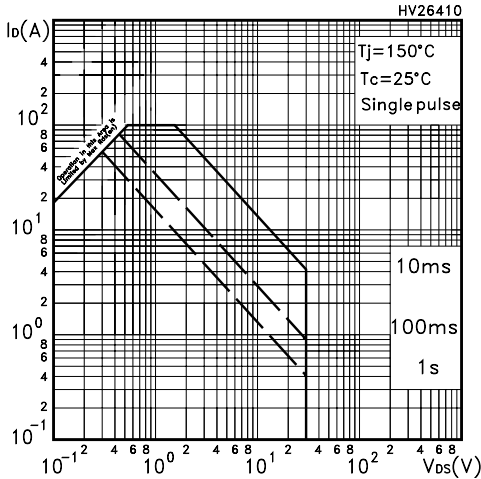


Figure 4: Output Characteristics

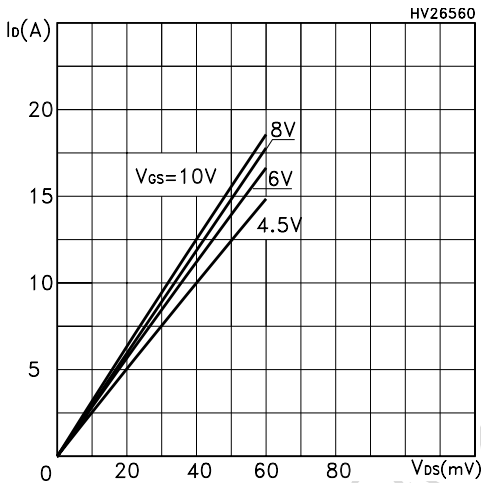


Figure 5: Transconductance

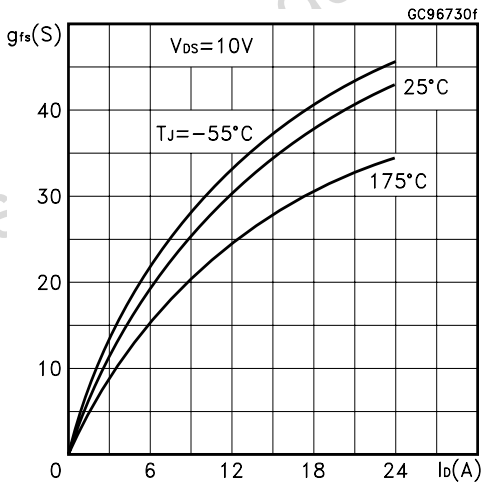


Figure 6: Thermal Impedance

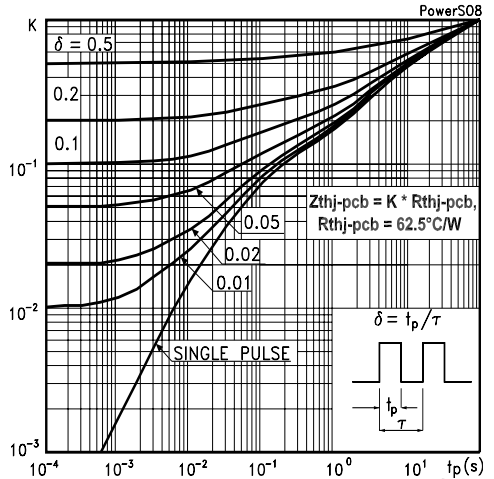


Figure 7: Transfer Characteristics

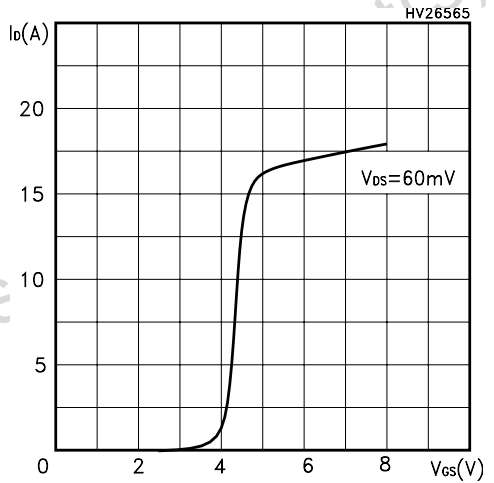


Figure 8: Static Drain-source On Resistance

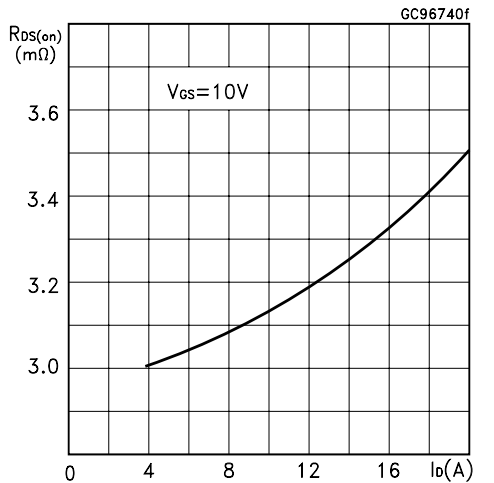


Figure 9: Gate Charge vs Gate-source Voltage

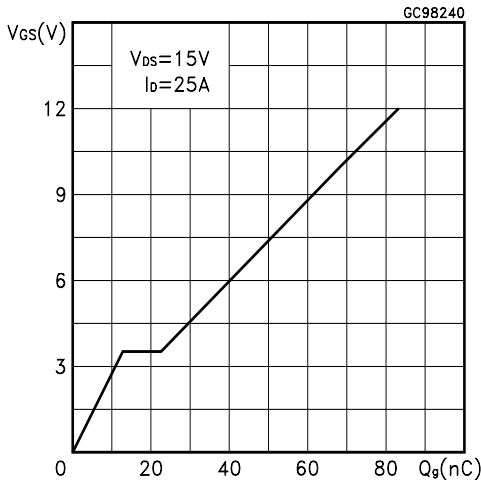


Figure 10: Normalized Gate Threshold Voltage vs Temperature

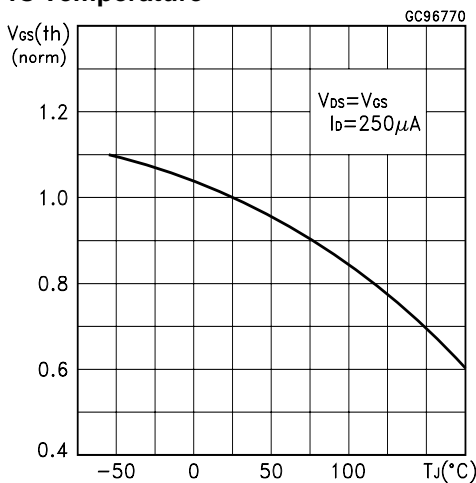


Figure 11: Normalized On Resistance vs Temperature

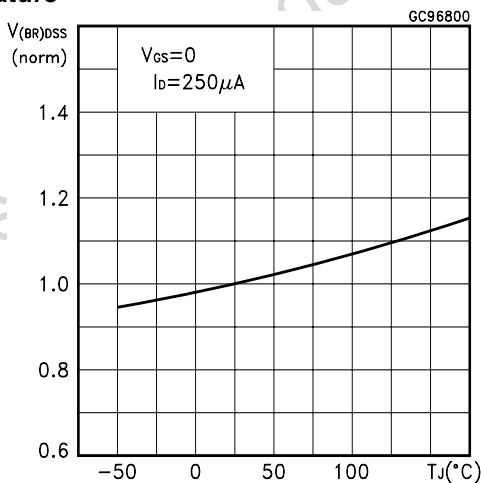


Figure 12: Capacitance Variations

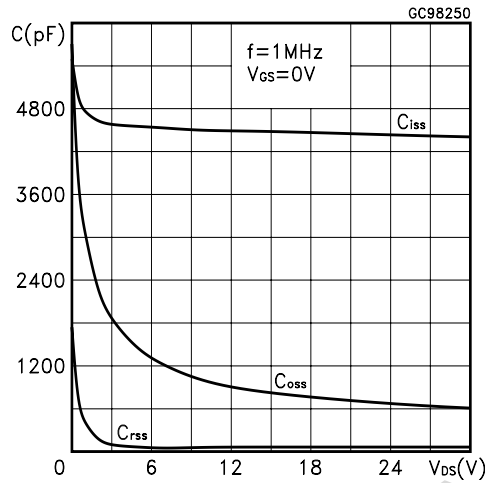


Figure 13: Normalized BVDSS vs Temperature

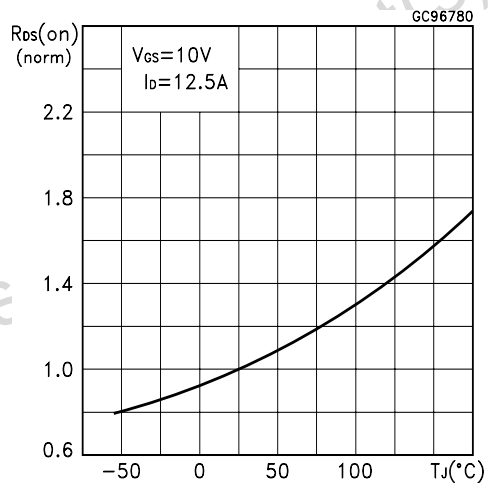


Figure 14: Source-Drain Diode Forward Characteristics

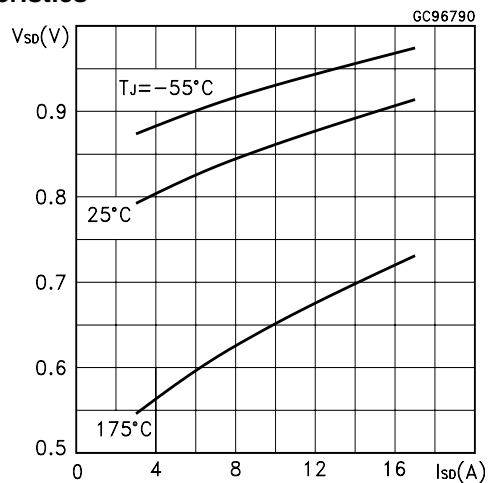
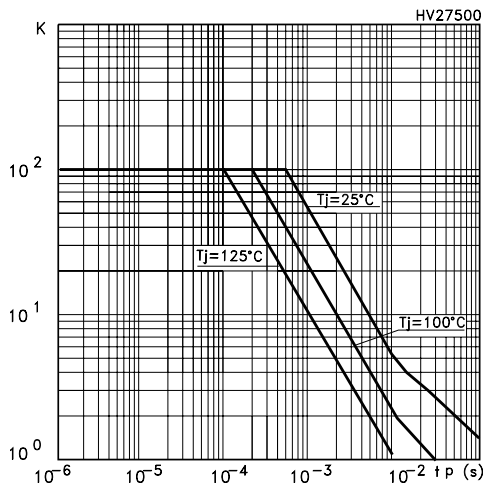


Table 11: Allowable  $I_{AV}$  vs. Time in Avalanche



The previous curve gives the single pulse safe operating area for unclamped inductive loads, under the following conditions:

$$P_{D(AVE)} = 0.5 \cdot (1.3 \cdot BV_{DSS} \cdot I_{AV})$$

$$E_{AS(AR)} = P_{D(AVE)} \cdot t_{AV}$$

Where:

$I_{AV}$  is the Allowable Current in Avalanche

$P_{D(AVE)}$  is the Average Power Dissipation in Avalanche (Single Pulse)

$t_{AV}$  is the Time in Avalanche

Figure 15: Switching Times Test Circuit For Resistive Load

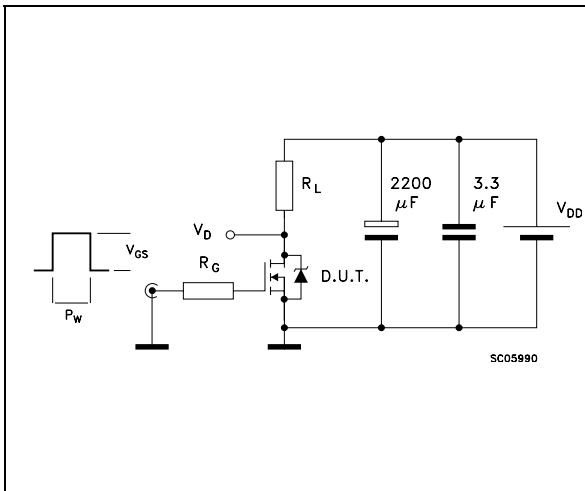


Figure 16: Test Circuit For Diode Recovery Times

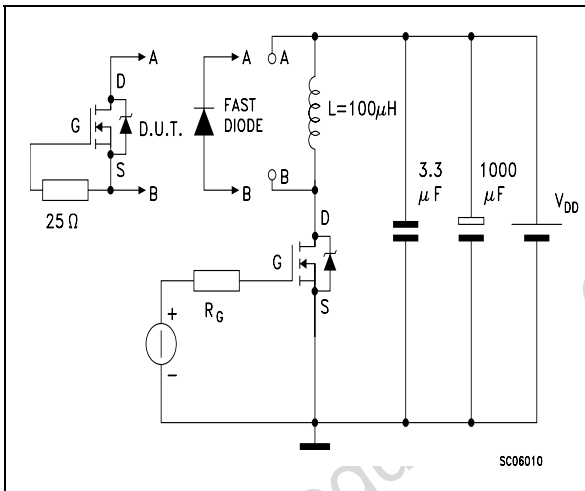
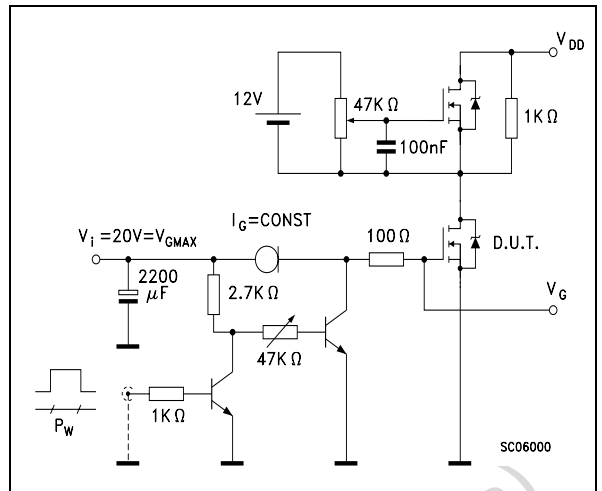


Figure 17: Gate Charge Test Circuit



Obsolete Product(s)

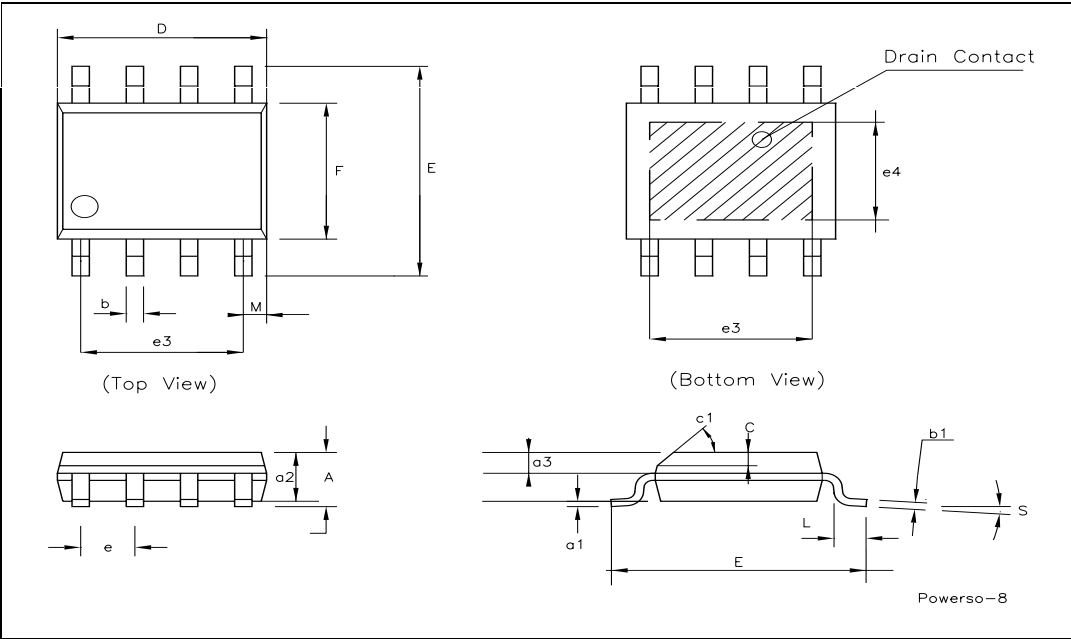
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: [www.st.com](http://www.st.com)

Obsolete Product(s) - Obsolete Product(s)



**PowerSO-8™ MECHANICAL DATA**

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
C	0.25		0.5	0.010		0.019
c1	45° (typ.)					
D	4.8		5.0	0.188		0.196
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		3.81			0.150	
e4		2.79			0.110	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
M			0.6			0.023
S	8° (max.)					



**Table 12: Revision History**

<b>Date</b>	<b>Revision</b>	<b>Description of Changes</b>
14-Sep-2004	2	Preliminary Data.
23-May-2005	3	New values on table 5
29-Jun-2005	4	New $R_G$ value on table 6
16-Nov-2005	5	Complete version

Obsolete Product(s) - Obsolete Product(s)

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